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**REPLY UNDER 37 CFR 1.116
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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No.:	10/707,388	Conf. No.:	1387
Filing Date:	12/10/2003	Art Unit:	2891
Applicant:	Divakaruni et al.	Examiner:	Fulk, Steven J.
Title:	SILICIDE RESISTOR IN BEOL LAYER OF SEMICONDUCTOR DEVICE AND METHOD	Docket No.:	FIS920030274 (IBMF-0032)

COMMISSIONER FOR PATENTS


DESTINATION FACSIMILE NUMBER: 571-273-8300

Transmitted herewith is: **After-Final Amendment in 10 pages**
in the above identified application.

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January 9, 2006
Date

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re Application of: Divakaruni et al.	Conf. No.: 1387
Serial No.: 10/707,388	Art Unit: 2891
Filed: 12/10/2003	Dkt. #: FIS920030274US1 (IBMF-0032)
Title: SILICIDE RESISTOR IN BEOL LAYER OF SEMICONDUCTOR DEVICE AND METHOD	Examiner: Fulk, Steven J.

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Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

AFTER-FINAL REQUEST FOR RECONSIDERATION

Sir:

I. INTRODUCTORY COMMENTS:

In response to the final Office Action of November 10, 2005, please reconsider the above-referenced patent application as follows: